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Chiral and *meso*-bis([2.2]paracyclophan-4-yl)methane and *meso*bis([2.2]paracyclophan-4-yl) sulfide

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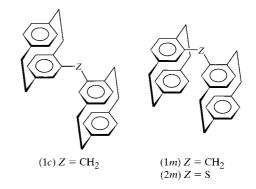
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The [2.2]paracyclophane groups of the title compounds, chiral and *meso*-bis(tricyclo[8.2.2.2^{4,7}]hexadeca-4,6,10,12,13,15-hexaen-5-yl)methane (the former as a racemate), $C_{33}H_{32}$, and *meso*-bis(tricyclo[8.2.2.2^{4,7}]hexadeca-4,6,10,12,13,15-hexaen-5-yl) sulfide, $C_{32}H_{30}S$, show the characteristic structural features of the parent compound [2.2]paracyclophane and the related compound dimethylbis([2.2]paracyclophan-4-yl)silane, $C_{34}H_{36}Si$: the aromatic rings are puckered, resulting in a boat conformation. The planes of the four coplanar C atoms are slightly twisted with respect to each other. The $Csp^3 - Csp^3$ bond lengths of the ethylene bridges are elongated by the electronic and steric effects of the skeleton.

Comment

Because of the (planar) chirality of monosubstituted [2.2]paracyclophanes (Q), compounds ZQ_2 composed of a central atom or group (Z) carrying two Q ligands can occur as meso and chiral diastereomers. Some time ago we reported the X-ray structures of the first pair of such diastereomers, in which Z was $Si(CH_3)_2$ (Jones et al., 1997), and recently the structure of *meso*-bis[2.2]paracyclophan-4-yl (Z = nil) has been determined (Jones & Kuś, 1998). The configurations of the title compounds, (1c) and (1m), as determined by NMR data, where the chemical equivalence or non-equivalence of the H atoms of the central methylene group indicate the chiral or meso-configuration, respectively, were confirmed by the X-ray structures; (1c) crystallizes as a racemate with imposed twofold symmetry. The X-ray diffraction study of the sulfide, (2m), was necessary because NMR data gave no indication of its configuration.

The paracyclophanyl groups in the title compounds show the characteristic structural features of substituted [2.2]paracyclophanes, similar to the diastereomeric pair of dimethylbis[2.2]paracyclophan-4-yl)silanes, $C_{34}H_{36}Si$, (3) (Jones *et al.*, 1997) (Figs. 1–3). The aromatic rings are distorted into boat shapes and the C atoms bearing the ethylene bridges are displaced out of the plane of the four other atoms. The mean aromatic planes are slightly inclined with respect to one another; the angles within paracyclophanyl groups vary from 0.3 (2) in (2*m*) to 1.7 (1)° in (1*m*), *cf.* 1.6 (4) to 4.5 (4)° in (3).



The *para*-C atoms are displaced out of the planes by amounts similar to those in the parent compound (4), [2.2]-paracyclophane (0.156 and 0.157 Å; Stalke, 1996). The values vary from 0.153 (2) to 0.172 (2) in (1c), 0.146 (2) to 0.160 (2) in (1m) and 0.140 (3) to 0.167 (3) Å in (2m). In contrast to the diastereomeric pair (3), no differences in the displacements between the substituted and non-substituted rings can be recognized.

The non-bonded distances of the corresponding bridgehead C atoms, which eclipse one another transannularly, are less than 2.8 Å [2.780 (2) and 2.792 (2) in (1c), 2.767 (2) to 2.774 (2) in (1m) and 2.763 (3) to 2.777 (3) Å in (2m)]. The intramolecular separation of the planes results in values of 3.084 (2) to 3.135 (2) in (1c), 3.041 (2) to 3.128 (2) in (1m) and 3.052 (3) to 3.098 (3) Å in (2m). The deviations from the geometry of the parent compound (4) (2.779 and 3.093 Å;

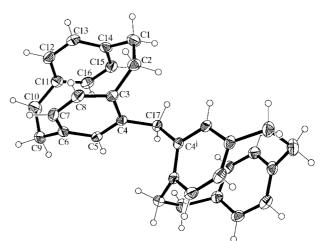


Figure 1

The molecule of compound (1*c*) in the crystal. Ellipsoids correspond to 50% probability levels. H atom radii are arbitrary. [Symmetry code: (i) 1 - x, y, $\frac{3}{2} - z$].

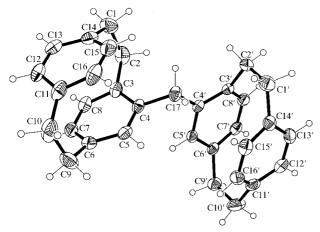


Figure 2

The molecule of compound (1m) in the crystal. Ellipsoids correspond to 50% probability levels. H atom radii are arbitrary.

Stalke, 1996) are less pronounced than in the diastereomeric pair of (3) with their bulkier central $Si(CH_3)_2$ moieties.

The torsion angle $C9\cdots C2-C1\cdots C10$ indicates a mutual twist of the aromatic rings. Individual values are 4.61 (3) $(C9\cdots C2-C1\cdots C10)$ in (1c), -1.26 (4) $(C9\cdots C2-C1\cdots C10)$ and 2.00 (4)° $(C9'\cdots C2'-C1'\cdots C10')$ in (1m). The sulfur-bridged compound, (2m), displays values of 4.64 (5) $(C9\cdots C2-C1\cdots C10)$ and -0.90 (5)° $(C9'\cdots C2'-C1'\cdots C10')$.

As usual, the $Csp^3 - Csp^3$ bonds of the ethylene bridges are characteristically elongated to values of 1.581 (2) and 1.585 (2) in (1c), 1.577 (2) to 1.582 (3) in (1m) and 1.572 (3) to 1.580 (3) Å in (2m), similar to the parent compound (4) (1.571 Å; Stalke, 1996).

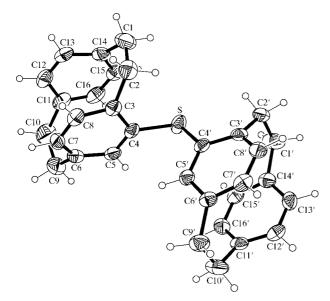


Figure 3

The molecule of compound (2m) in the crystal. Ellipsoids correspond to 50% probability levels. H atom radii are arbitrary.

The carbon–carbon bonds in (1c) and (1m) and the sulfur– carbon bonds in (2m) between the two halves of the molecules lie in the range of the mean standard bond length of 1.513 Å for a Csp^3-C_{ar} (Allen *et al.*, 1987) and 1.768 Å for a $C_{ar}-S$ bond length (Allen *et al.*, 1987): 1.518 (2) in (1c), 1.513 (2) and 1.521 (2) in (1m), and 1.778 (2) and 1.780 (2) Å in (2m).

The torsion angles C5-C4-Z-C4' and C4-Z-C4'-C5'indicate the orientation of the paracyclophane groups with respect to each other. The central bond C4-Z in all cases shows torsion angles close to 120° and thus an *ac* conformation: -113.80 (12) [C5-C4-C17-C4ⁱ; symmetry code: (i) 1 $-x, y, \frac{3}{2} - z$] in (1*c*), 106.24 (15) (C5-C4-C17-C4') in (1*m*) and -111.86 (16)° (C5-C4-S-C4') in (2*m*). In contrast, the bond Z-C4' has a flattened *sc* conformation: -30.64 (19) (C4-C17-C4'-C5') in (1*m*) and 33.75 (18)° (C4-S-C4'-C5') in (2*m*).

Experimental

The title compounds were prepared according to the method of Ernst & Wittkowski (1999).

Compound (1c)

Crystal data

C33H32 Mo $K\alpha$ radiation $M_r = 428.59$ Cell parameters from 64 Monoclinic, C2/c reflections a = 24.928 (3) Å $\theta = 4.8 - 12.5^{\circ}$ $\mu = 0.071 \text{ mm}^{-1}$ b = 7.8409 (6) Å c = 11.5716 (12) ÅT = 173 (2) K $\beta = 92.256 \ (8)^{\circ}$ Hexagonal tablet, colourless V = 2260.0 (4) Å² $0.76 \times 0.46 \times 0.22 \text{ mm}$ Z = 4Crystal source: Ernst & Wittkowski $D_x = 1.260 \text{ Mg m}^{-3}$ (1999)

Data collection

Siemens P4 diffractometer ω scans 3066 measured reflections 2589 independent reflections 1912 reflections with $I > 2\sigma(I)$ $R_{\text{int}} = 0.025$ $\theta_{\text{max}} = 27.49^{\circ}$

Refinement

Refinement on F^2 $w = 1/[\sigma^2(F_o^2) + (0.0763P)^2]$ $R[F^2 > 2\sigma(F^2)] = 0.045$ + 0.4887P] where $P = (F_o^2 + 2F_c^2)/3$ $wR(F^2) = 0.131$ S = 1.024 $(\Delta/\sigma)_{\rm max} < 0.001$ $\Delta \rho_{\rm max} = 0.27 \ {\rm e} \ {\rm \AA}^{-3}$ 2587 reflections $\Delta \rho_{\rm min} = -0.21 \text{ e } \text{\AA}^{-3}$ 151 parameters Extinction correction: SHELXL93 H-atom parameters constrained (Sheldrick, 1993) Extinction coefficient: 0.0080 (12)

 $h = 0 \rightarrow 32$ $k = -10 \rightarrow 2$

 $l = -15 \rightarrow 15$

3 standard reflections

every 247 reflections

intensity decay: none

Table 1

(

Selected geometric parameters (Å, $^{\circ}$) for (1c).

C4-C17	1.518 (2)	C17-C4 ⁱ	1.518 (2)
C5-C4-C17-C4 ⁱ	-113.80 (12)		
Symmetry code: (i) 1 -	$x, y, \frac{3}{2} - z.$		

organic compounds

Compound (1 <i>m</i>)	Table 3Selected geometric parameters (Å, $^{\circ}$) for (2m).				
Crystal data			/_>		
$C_{33}H_{32}$	Mo $K\alpha$ radiation	S-C4	1.778 (2)	S-C4′	1.780 (2)
$M_r = 428.59$ Monoclinic, $C2/c$ a = 25.969 (3) Å	Cell parameters from 64 reflections $\theta = 5.3-12.5^{\circ}$	C4′-S-C4-C5	-111.9 (2)	C4-S-C4′-C5′	33.8 (2)
b = 7.7200 (10) Å c = 23.329 (3) Å $\beta = 94.044 (6)^{\circ}$	$\mu = 0.069 \text{ mm}^{-1}$ T = 173 (2) K Tablet, colourless				
$V = 4665.3 (10) \text{ Å}^3$ Z = 8 $D_x = 1.220 \text{ Mg m}^{-3}$	1.20 × 0.64 × 0.34 mm Crystal source: Ernst & Wittkowski (1999)	<i>Refinement</i>			
Data collection		Refinement on F^2 $R[F^2 > 2\sigma(F^2)] = 0.04$	40	H-atom parameters co $w = 1/[\sigma^2(F_o^2) + (0.04)]$	
Siemens P4 diffractometer ω scans 4268 measured reflections 4095 independent reflections 3240 reflections with $I > 2\sigma(I)$ $R_{int} = 0.011$	$h = -30 \rightarrow 30$ $k = -9 \rightarrow 1$ $l = -27 \rightarrow 0$ 3 standard reflections every 247 reflections intensity decay: none	$wR(F^2) = 0.090$ S = 0.817 4115 reflections 298 parameters		$P = (F_o^2 + 2F_c^2)/3$ $\Delta \rho_{\text{max}} = 0.27 \text{ e } \text{\AA}^{-3}$ $\Delta \rho_{\text{min}} = -0.18 \text{ e } \text{\AA}^{-3}$	
$\theta_{\rm max} = 25^{\circ}$		For compound	(1m) very few	single crystals were av	vailable, and
Refinement		•	· / ·	they deformed: the ci	
Refinement on F^2 $R[F^2 > 2\sigma(F^2)] = 0.042$ $wR(F^2) = 0.116$	H-atom parameters constrained $w = 1/[\sigma^2(F_o^2) + (0.0671P)^2 + 1.7940P]$	therefore greater than would normally be acceptable. For $(2m)$, which diffracted more weakly, 307 similarity restraints were applied to the U^{ij} components of C atoms.			

1.521(2)

-30.6(2)

For all compounds, data collection: XSCANS (Fait, 1991); cell refinement: XSCANS; data reduction: XSCANS; program(s) used to solve structure: SHELXS86 (Sheldrick, 1990); program(s) used to refine structure: SHELXL93 (Sheldrick, 1993); molecular graphics: XP5 (Siemens, 1994); software used to prepare material for publication: SHELXL93.

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Supplementary data for this paper are available from the IUCr electronic archives (Reference: BM1382). Services for accessing these data are described at the back of the journal.

References

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Stalke, D. (1996). Private communication.

5091 measured reflections
4117 independent reflections
2443 reflections with $I > 2\sigma(I)$
$R_{\rm int} = 0.019$
$\theta_{\rm max} = 25^{\circ}$

Siemens P4 diffractometer

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S = 1.037

Table 2

C4-C17

C5-C4-C17-C4'

Compound (2m)

Crystal data

 $M_r = 446.62$

Triclinic, P1

 $a = 8.1084 (12) \text{ \AA}$

b = 12.334 (2) Å

c = 12.826(2) Å

 $\alpha = 94.525 \ (12)^{\circ}$

 $\beta = 105.516 (12)^{\circ}$

 $\gamma = 105.779 \ (8)^{\circ}$

Z = 2

 ω scans

V = 1173.3 (3) Å³

Data collection

 $C_{32}H_{30}S$

4094 reflections

298 parameters

Selected geometric parameters (Å, $^{\circ}$) for (1*m*).

1.513(2)

106.2 (2)

Cell parameters from 55 reflections $\theta = 5.5 - 12.5^{\circ}$ $\mu = 0.157 \text{ mm}^{-1}$ T = 173 (2) KTablet, colourless $0.60 \times 0.30 \times 0.08 \text{ mm}$ Crystal source: Ernst & Wittkowski (1999)

 $h = -9 \rightarrow 5$ $k = -14 \rightarrow 14$ $l = -14 \rightarrow 15$ 3 standard reflections every 247 reflections intensity decay: 3%

C17-C4′

where $P = (F_o^2 + 2F_c^2)/3$ $\Delta \rho_{\text{max}} = 0.18 \text{ e Å}^{-3}_{\circ}$

 $\Delta \rho_{\rm min} = -0.23 \text{ e} \text{ Å}^{-3}$

C4-C17-C4'-C5'

 $D_x = 1.264 \text{ Mg m}^{-3}$

Mo $K\alpha$ radiation

Acta Cryst. (2000). C56, 239-241